

Report No. MCR-22-0738

Date: Dec./1/2022

RENESAS SEMICONDUCTOR RELIABILITY REPORT

SERIES : RL78/F12

DEVICE : R5F1096xySP/R5F1096xyXXXSP

(x=8/A/B/C/D/E,y=J/K)

APPLICATION: Automobile

Quality Assurance Div. Renesas Electronics Corporation

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$Q100\ Qualification\ Test\ Results\ for\ R5F1096xySP/R5F1096xyXXXSP(x=8/A/B/C/D/E,y=J/K)$

[Note: Basically qualification tests were performed using a representative product with the same wafer process and the same package structure.]

	Test # Reference Test Conditions Lots S.S. Total Results Comments:											
Test	#	Reference	Test Conditions			S.S.	Total	(Fail of Total)	(N/A =Not Applicable)			
			TEST GRO	OUP A – ACCELERAT	ED ENVIR	RONMENT S	STRESS TE	ESTS				
PC	A1	JESD22 A113 J-STD-020	Preconditioning: (Test @ Rm) SMD only; Moisture Preconditioning for THB/HAST, AC/UHST, TC, &PTC Peak Reflow Temp=260°C			Min.MSL=3			-			
THB or HAST	A2	JESD22 A101	Temperature Humidity Bias: (Test @ Rm/Ho Ta=85°C, RH=85%, 1000hrs	ot)	3	77	231	0 of 231	-			
AC or UHST or TH	A3	JESD22 A102	Autoclave : (Test @ Rm) Ta=121°C, P=2atm, RH=100%, 96hrs			77	231	0 of 231	-			
TC	A4	JESD22 A104	Temperature Cycle: (Test @ Hot) Ta=-65°C to 150°C, 500cyc			77	231	0 of 231	-			
PTC	A5	JESD22 A105	Power Temperature Cycle: (Test @ Rm/Hot)	-	-	-	-	N/A				
HTSL	A6	JESD22 A103	High Temperature Storage Life: (Test @ Rm Ta=150°C, 1000hrs	/Hot)	1	45	45	0 of 45	-			
			TEST GRO	OUP B – ACCELERAT	TED LIFET	IME SIMU	LATION TI	ESTS				
HTOL	B1	JESD22 A108	High Temp Operating Life: (Test @ Rm/Col Ta=125°C, 1000hrs	3	77	231	0 of 231	-				
ELFR	B2	AEC-Q100-008	Early Life Failure Rate: (Test @ Rm/Hot) Ta=125°C, 48hrs	3	800	2400	0 of 2400	-				
EDR	В3	AEC-Q100-005	NVM Endurance & Data Retention Test:	For HTOL	3	77	231	0 of 231	-			
	23	Q100 000	(Test @ Rm/Hot)	For HTSL	1	45	45	0 of 45	-			

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP C – PACKAG	E ASSEMB	LY INTEG	RITY TEST	'S	
WBS	C1	AEC-Q100-001	Wire Bond Shear Test: (Ppk > 1.67 and Cpk > 1.33)	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Ppk>1.67
WBP	C2	Mil-STD-883 Method 2011	Wire Bond Pull: (Ppk > 1.67 and Cpk > 1.33); Each bonder used	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Ppk>1.67
SD	С3	JESD22 B102	Solderability: (>95% coverage) Solder temp: 245C, Solder Immersion time: 5sec	1	15	15	0 of 15	-
PD	C4	JESD22 B100, JESD22 B108	Physical Dimensions: (Ppk > 1.67 and Cpk > 1.33)	3	10	30	0 of 30	Ppk>1.67
SBS	C5	AEC-Q100-010	Solder Ball Shear: (Ppk > 1.67 and Cpk > 1.33)	-	-	-	-	N/A
LI	C6	JESD22 B105	Lead Integrity: (No lead cracking or breaking); Through-hole only	-	-	-	-	N/A
			TEST GROUP D – DIE FAB	RICATION	RELIABII	ITY TESTS	S	
EM	D1	JESD61	Electromigration:	-	-	-	Pass	Confirmed by process TEG
TDDB	D2	JESD35	Time Dependant Dielectric Breakdown:	-	-	-	Pass	Confirmed by process TEG
HCI	D3	JESD60 & 28	Hot Carrier Injection:	-	-	-	Pass	Confirmed by process TEG
NBTI	D4	JESD90	Negative Bias Temperature Instability:	-	-	-	Pass	Confirmed by process TEG
SM	D5	JESD61,87 & 202	Stress Migration:	-	-	-	Pass	Confirmed by process TEG

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP E- ELE	CCTRICAL	VERIFICA	TION		
TEST	E1 User/Supplier Specification Pre and Post Stress Electrical Test:		Pre and Post Stress Electrical Test:	All	All	All	0 of All	-
HBM/ MM	E2	AEC-Q100-002 AEC-Q100-003	Electrostatic Discharge, Human Body Model / Machine Model: (Test @ Rm/Hot); (2KV HBM / 200V MM) At least one of these models must be performed.	1	HBM:3 MM:3	6	0 of 6 ESD Level= HBM: H2 MM: M3	HBM: 2000V Pass MM: 200V Pass
CDM	Е3	AEC-Q100-011	Electrostatic Discharge, Charged Device Model: (Test @ Rm/Hot); (750V corner leads, 500V all other leads)	1	3	3	0 of 3 ESD Level= CDM: C4B	Corner leads: 750V Pass All other leads:500V Pass *Only Direct charge method
LU	E4	AEC-Q100-004	Latch-Up: (Test @ Rm/Hot)	1	6	6	0 of 6	-
ED	E5	AEC-Q100-009 AEC-Q003	Electrical Distributions: (Test @ Rm/Hot/Cold) (Cpk > 1.33, Ppk > 1.67)	3	30	90	0 of 90	Ppk>1.67
FG	E6	AEC-Q100-007	Fault Grading:	-	-	-	>98%	-
CHAR	E7	AEC-Q003	Characterization: (Test @ Rm/Hot/Cold)	-	-	-	Pass	According to Renesas standard procedure
GL	E8	AEC-Q100-006	Electro-Thermally Induced Gate Leakage: (Test @ Rm)	1	6	6	0 of 6	-
EMC	E9	SAE J1752/3	Electromagnetic Compatibility (Radiated Emissions)	1	1	1	0 of 1	-
SC	E10	AEC Q100-012	Short Circuit Characterization	i	-	-	-	N/A
SER	E11	JESD89-1 JESD89-2 JESD89-3	Soft Error Rate	1	3	3	Pass	-

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)		
			TEST GROUP F – DE	FECT SCR	EENING T	ESTS				
PAT	F1	AEC-Q001	Process Average Testing: (see AEC-Q001)	All	All	All	Reject units outside PAT limits	Apply to mass production according to Renesas standard procedure		
SBA	F2	AEC-Q002	Statistical Bin/Yield Analysis: (see AEC-Q002)	All	All	All	Reject units outside criteria	Apply to mass production according to Renesas standard procedure		
	TEST GROUP G - CAVITY PACKAGE INTEGRITY TESTS (for Ceramic Package testing only)									
MS	G1	JESD22 B104	Mechanical Shock: (Test @ Rm)	-	-	-	-	N/A		
VFV	G2	JESD22 B103	Variable Frequency Vibration: (Test @ Rm)	-	-	-	-	N/A		
CA	G3	MIL-STD-883 Method 2001	Constant Acceleration: (Test @ Rm)	-	-	-	-	N/A		
GFL	G4	MIL-STD-883 Method 1014	Gross and Fine Leak:	-	-	-	-	N/A		
DROP	G5		Drop Test: (Test @ Rm) MEMS cavity parts only. Drop part on each of 6 axes once from a height of 1.2m onto a concrete surface.	-	-	-	-	N/A		
LT	G6	MIL-STD-883 Method 2004	Lid Torque:	-	-	-	-	N/A		
DS	G7	MIL-STD-883 Method 2019	Die Shear:	-	-	-	-	N/A		
IWV	G8	MIL-STD-883 Method 1018	Internal Water Vapor:	-	-	-	-	N/A		

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Calculation method of standard failure rate

Target: 0.13um CMOS process product (RL78 series Automobile)

Operating reliability is decided by inherent reliability of device and environment condition of use (See below).

Calculation method of standard failure rate (λ)

(1)Basic failure rate(λb)

λb: 0.18 (FIT)

(2)Temperature parameter

$$\pi T = \exp \left\{ 11600 \times \text{Ea} \times \left(\frac{1}{273+55} - \frac{1}{273+\text{Ta}} \right) \right\}$$

Ea : Activation energy (eV)
Ta : ambient temperature

πT Simplified chart (Ea=0.7eV)												
Ta(°C)	40	50	55	60	65	70	75	80	85	90	100	110
πΤ	0.31	0.68	1	1.45	2.08	2.95	4.15	5.77	7.96	10.88	19.82	34.99

-Confidence level 60% -Standard temperature Ta=55°C

(3)MTTF (Mean Time To Failure)
$$MTTF = \frac{1}{\lambda}$$



Product list Report No. MCR-22-0738

	uct list					керс	ort No. MCR-22-0/38
No	Group	Product part number	Package code	No	Group	Product part number	Package code
1	RL78/F12	R5F10968JSP	PLSP0020JC-A	51			
2	RL78/F12	R5F10968JXXXSP	PLSP0020JC-A	52			
3	RL78/F12	R5F10968KSP	PLSP0020JC-A	53			
4	RL78/F12	R5F10968KXXXSP	PLSP0020JC-A	54			
5	RL78/F12	R5F1096AJSP	PLSP0020JC-A	55			
6	RL78/F12	R5F1096AJXXXSP	PLSP0020JC-A	56			
7	RL78/F12	R5F1096AKSP	PLSP0020JC-A	57			
8	RL78/F12	R5F1096AKXXXSP	PLSP0020JC-A	58			
9	RL78/F12	R5F1096BJSP	PLSP0020JC-A	59			
10	RL78/F12	R5F1096BJXXXSP	PLSP0020JC-A	60			
11	RL78/F12	R5F1096BKSP	PLSP0020JC-A	61			
12	RL78/F12	R5F1096BKXXXSP	PLSP0020JC-A	62			
13	RL78/F12	R5F1096CJSP	PLSP0020JC-A	63			
14	RL78/F12	R5F1096CJXXXSP	PLSP0020JC-A	64			
15	RL78/F12	R5F1096CKSP	PLSP0020JC-A	65			
16	RL78/F12	R5F1096CKXXXSP	PLSP0020JC-A	66			
17	RL78/F12	R5F1096DJSP	PLSP0020JC-A	67			
18	RL78/F12	R5F1096DJXXXSP	PLSP0020JC-A	68			
19	RL78/F12	R5F1096DKSP	PLSP0020JC-A	69			
20	RL78/F12	R5F1096DKXXXSP	PLSP0020JC-A	70			
21	RL78/F12	R5F1096EJSP	PLSP0020JC-A	71			
22	RL78/F12	R5F1096EJXXXSP	PLSP0020JC-A	72			
23	RL78/F12	R5F1096EKSP	PLSP0020JC-A	73			
24	RL78/F12	R5F1096EKXXXSP	PLSP0020JC-A	74			
25	1 1 2 7 3 7 1 1 2	1.0. 10001.000.0.	. 20. 002030 71	75			
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38				88			
39	+			89	+		
40	+			90	+		
41	+			91	+		
42	+			92			
43	1			93			
44	+			94			
44 45	+			95	+		
	+				1		
46	-			96	1		
47				97			
48				98	1		
49	1			99	1		
50				100			